

FCC TEST REPORT

APPLICANT

KPhone USA Inc.

PRODUCT NAME

smart phone

MODEL NAME

K5

TRADE NAME

KPHONE

BRAND NAME

KPHONE

FCC ID

2AFJ5K5

STANDARD(S)

47 CFR Part 15 Subpart B

TEST DATE

2015-08-10 to 2015-09-10

ISSUE DATE

Certification

TECHNOLOGY Co., Ltd. SHENZHEN MORLAB COMMUNICATIONS

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	Change History					
Issue Date Reason for change						
1.0	2015-09-14	First edition				
ORL	Mo.	The topic more in the topic				



Test Report Declaration

Applicant	KPhone USA Inc.				
Applicant Address	8333 Foothill Blvd.#840 Rancho Cucamonga, CA 91730				
Manufacturer	Beijing Benywave Wireless Communication Co., Ltd.				
Manufacturer Address	No. 55, Jiachuang 2 Road, Beijing OPTO-Mechatronics Industrial Park (OIP), Tongzhou District, Beijing, China 101111				
Product Name	smart phone				
Model Name	K5				
Brand Name	KPHONE				
HW Version	TBT5755_P2_001				
SW Version	575511_1001_VXXXX				
Test Standards	47 CFR Part 15 Subpart B				
Test Result	PASS				

Tested by	:	(ai lun long	- 4	
		3.4.00		

Cai Junlong (Test Engineer)

Xiao Xiong Xiao Xiong (EMC Manager) Reviewed by

Zeng Devin Zeng Dexin (Chief Engineer) Approved by



1. Technical Information

Note: Provide by applicant.

1.1. Applicant Information

Company: KPhone USA Inc.

Address: 8333 Foothill Blvd.#840 Rancho Cucamonga, CA 91730

1.2. Equipment under Test (EUT) Description

EUT Type:	smart phone
Serial No:	(n.a., marked #1 by test site)
Hardware Version:	TBT5755_P2_001
Software Version:	575511_1001_VXXXX

Power supply:	Battery	O. LAB ORLE MO.	
ORLA	Brand Name:	N/A	
	Model No.:	TBT5728A	
	Serial No.:	(n.a. marked #1 by test site)	
	Capacity:	2920mAh	
	Rated Voltage:	3.85V	
	Charge Limit:	4.4V	
Ancillary Equipment1:	AC Adapter (Charger for Battery)		
	Brand Name:	KPHONE	
	Model No.:	SC/10WG050200US	
	Serial No.:	(n.a. marked #1 by test site)	
	Rated Input:	~ 100-240V, 50/60Hz, 500mA	
	Rated Output:	= 5V, 2000mA	
Ancillary Equipment2:	USB Cable	3 LAP ORL MO	
The More in	Length:	100cm	
	Type:	shielded cable	
Ancillary Equipment3:	Earphone	TELL HO. I III JELLE	
ME AB CALAL	Length:	150cm	
	Type:	In Ear Monitor	

NOTE:

1. The Smartphone contains two SIM card slots, and the Smartphone supports Dual Standby



but without Dual Active, they share the same software and hardware(RF module and Power supply, etc.). When a call is established on one SIM card, the other is no longer active, callers to the other SIM will hear a message that the phone is switched off or they'll be redirected to voicemail. After pre-scan test, the SIM card 1 was the worst case, so we tested and recorded the results according to SIM card 1. It supports GSM850MHz, 900MHz,1900MHz, GPRS, EDGE, WCDMA Band I , Band II , Band IV , Band V , Band VIII , HSDPA, HSUPA, LTE Band1/4/7/17, GPS, FM, ISM 2.4GHz Bluetooth band and WIFI (802.11b/g/n) band.

- It is equipped with a Micro-B USB port which can be connected to the ancillary equipments
 e.g. the PC.
- 3. For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15(10-1-13 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	2015.09.10	PASS
2	15.109	Radiated Emission	2015.09.10	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



3. Test Conditions Setting

3.1. Test Mode

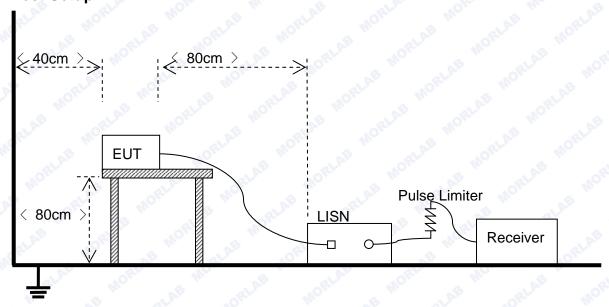
1 , 1	The first test mode (Data Transmission)				
	The EUT configuration of the emission tests is EUT + Battery + earphone + PC. In this test mode, the EUT with was connected to a PC via the Micro-B USB port. During the measurement, the data is transmitting between the PC and the EUT.				
2	The second test mode (Standby)				
	The EUT configuration of the emission tests is EUT + Battery + earphone + Charger. During the measurement, the EUT was charged by its adapter and turned on.				



3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity in maintained with respect to the impedance characteristics as prescribed in ANSI C63.4-2009 at Clause 4.3.

B. Equipments List:

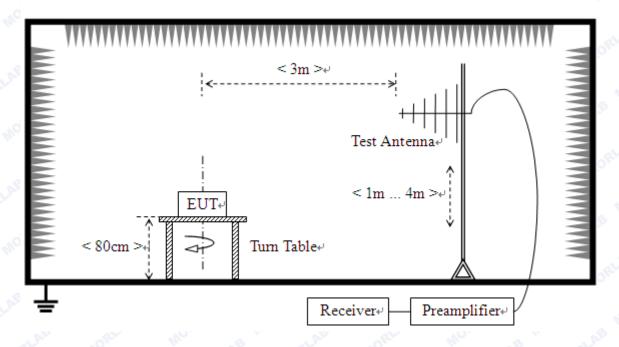
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2015.2.21	2016.2.20
EMC Analyzer	Agilent	E7405A	US44210471	2015.2.21	2016.2.20
LISN	Schwarzbeck	NSLK 8127	812744	2015.2.24	2016.2.23
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
PC HORL	Apple	A1370	C02FQ2PYD DQW	(n.a.)	(n.a.)



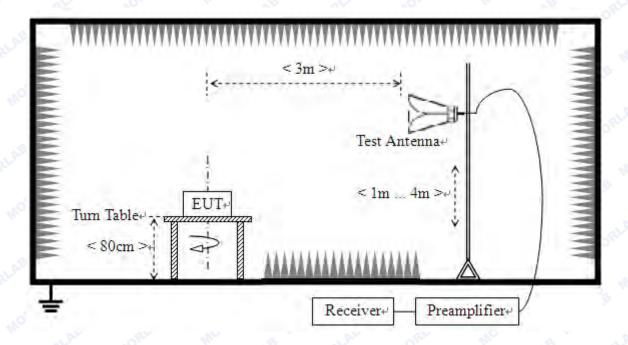
3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
EMC Analyzer	Agilent	E7405A	US44210471	2015.2.21	2016.2.20
Receiver	Narda	PMM 9060	001WX11001	2015.2.21	2016.2.20
Receiver	Narda	PMM 9010	595WX11007	2015.2.21	2016.2.20
Semi-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2015.2.21	2016.2.20
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2015.2.25	2016.2.24
Test Antenna - Horn	Schwarzbeck	BBHA 9120D	9120D-963	2015.2.25	2016.2.24
PC NOTE:	Apple	A1370	C02FQ2PYD DQW	(n.a.)	(n.a.)



4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu\text{H}/50\Omega$ line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBμV)				
(MHz)	Quasi-peak	Average			
0.15 - 0.50	66 to 56	56 to 46			
0.50 - 5	56	46			
5 - 30	60	50			

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

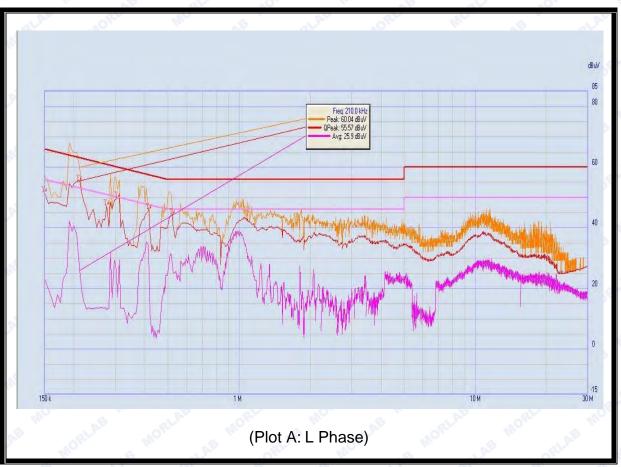
See section 3.2.1 of this report.

4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

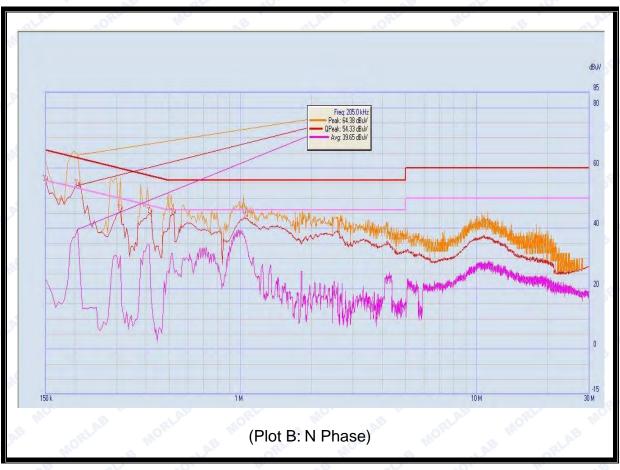
A. Test Plot and Suspicious Points:





No.		Emission Le	vel (dBµV)	Limit (d	dΒμV)	Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.15	51.72	23.17	66.00	56.00	ORLA	PASS
2	0.21	55.57	25.90	64.29	54.29	S ME LAF	PASS
3	0.275	47.45	13.08	62.43	52.43	Lino	PASS
4	0.305	49.90	17.20	61.57	51.57	Line	PASS
5	0.415	46.13	25.55	58.43	48.43	Jen Bull	PASS
6	0.52	44.48	27.69	56.00	46.00	ORLAN	PASS





No. Fre.		Emission Level (dBµV)		Limit (dΒμV)	Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		7 0 1 0 1 0 1
1,0	0.15	55.65	23.14	66.00	56.00	ORLA	PASS
2	0.205	54.33	39.65	64.43	54.43	e me	PASS
3	0.31	45.89	30.89	61.43	51.43	Maustral	PASS
4	0.415	44.95	26.33	58.43	48.43	Neutral	PASS
5	0.52	44.69	27.99	56.00	46.00	Okr B W	PASS
6	1.055	43.60	35.47	56.00	46.00	ORLAN	PASS

Test Result: PASS



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field Strength Limitation	at 3m Measurement Dist
range (MHz)	(μV/m)	(dBµV/m)
30.0 - 88.0	100	20log 100
88.0 - 216.0	150	20log 150
216.0 - 960.0	200	20log 200
Above 960.0	500	20log 500

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBµV/m is calculated by 20log Emission Level(µV/m).
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * (d2/d1)^{2.}

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

4.2.2. Test Description

See section 3.2.2 of this report.



4.2.3. Frequency range of measurement

Highest frequency generated or used in the device is the highest speed of the processor, lowest frequency generated or used in the device is the lowest frequency of the oscillator. According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

Frequency	Frequency generated or used in the device	Frequency range of radiated measurement in the report
Highest	1.2GHz	6.0GHz

4.2.4. Test Result

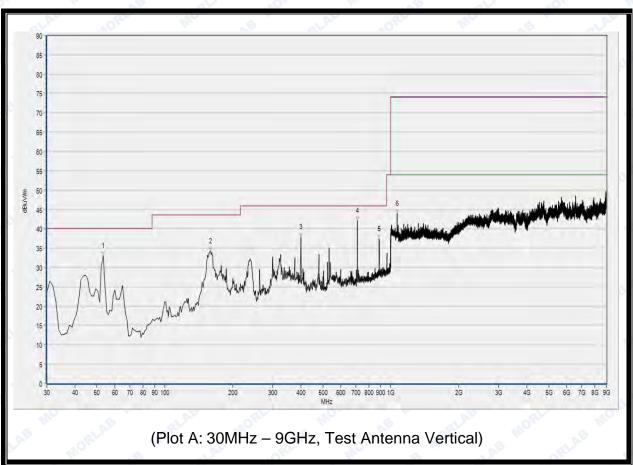
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

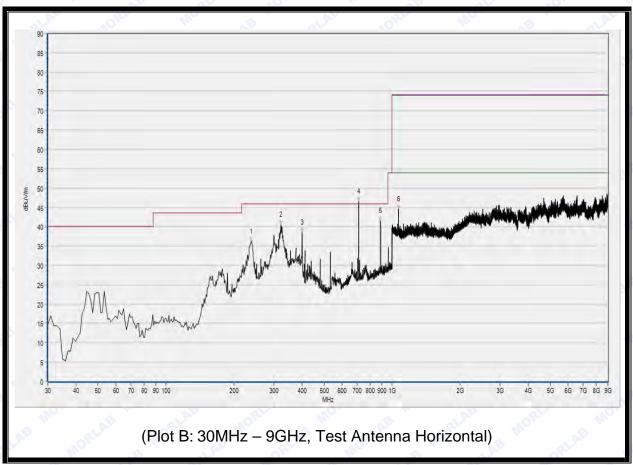
A. Test Plots and Suspicious Points:





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	RLAL	MORE
1	53.280	N.A	33.09	N.A	N.A	40.00	N.A	V	PASS
2	159.010	N.A	34.20	N.A	N.A	43.50	N.A	V	PASS
3	399.570	N.A	37.94	N.A	N.A	46.00	N.A	V	PASS
4	710.940	N.A	42.13	N.A	N.A	46.00	N.A	V	PASS
5	888.450	N.A	37.34	N.A	N.A	46.00	≫ N.A	V	PASS
6	1067.200	43.84	N.A	32.58	74.00	N.A	54.00	V	PASS





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	LAB	ORL
1	238.550	N.A	36.27	N.A	N.A	46.00	N.A	Н	PASS
2	321.970	N.A	40.60	N.A	N.A	46.00	N.A	Hall	PASS
3	399.570	N.A	38.52	N.A	N.A	46.00	N.A	Н	PASS
4	710.940	N.A	42.33	N.A	N.A	46.00	N.A	Н 🤞	PASS
5	888.450	N.A	41.57	N.A	N.A	46.00	N.A	Ĥ	PASS
6	1067.200	44.65	N.A	31.96	74.00	N.A	54.00	Н	PASS

Test Result: PASS



Annex A Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB





Annex B <u>Testing Laboratory Information</u>

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
RLA. MOR. NB MIC	Road, Block 67, BaoAn District, ShenZhen, GuangDong
	Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: The FCC registration number is 695796.

(Shenzhen Morlab Communications Technology Co., Ltd.)

4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

